

CYM1481A

Features

- High-density 16-megabit SRAM modules
- High-speed CMOS SRAMs

 Access time of 70 ns
- Low active power
 - —605 mW (max.), 2M x 8
- Double-sided SMD technology
- TTL-compatible inputs and outputs
- Small footprint SIP
 - PCB layout area of 0.72 sq. in.

• 2V data retention (L version)

Functional Description

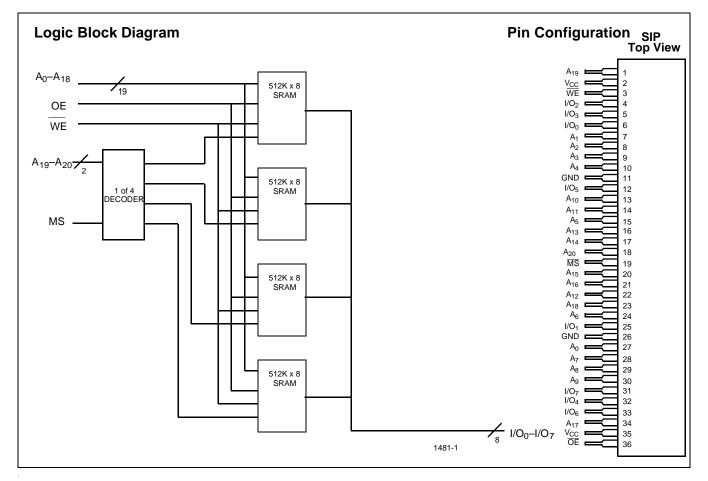
The CYM1481A is a high-performance 16-megabit static RAM module organized as 2048K words by 8 bits. These modules

2048K x 8 SRAM Module

are constructed from four 512K x 8 SRAMs in plastic surface-mount packages on an epoxy laminate board with pins. On-board decoding selects one of the SRAMs from the high-order address lines, keeping the remaining devices in standby mode for minimum power consumption.

An active LOW write enable signal ($\overline{\text{WE}}$) controls the writing/reading operation of the memory. When $\overline{\text{MS}}$ and $\overline{\text{WE}}$ inputs are both LOW, data on the eight data input/output pins is written into the memory location specified on the address pins. Reading the device is accomplished by selecting the device and enabling the outputs $\overline{\text{MS}}$ and $\overline{\text{OE}}$ active LOW while $\overline{\text{WE}}$ remains inactive or HIGH. Under these conditions, the content of the location addressed by the information on the address pins is present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the module is selected, outputs are enabled, and write enable $(\overline{\text{WE}})$ is HIGH.



Selection Guide

		CYM1481A				
Maximum Access Time (ns)	70	85	100	120		
Maximum Operating Current (mA)	110	110	110	110		
Maximum Standby Current (mA)	64	64	64	64		



Maximum Ratings

(Above which the useful life may be impaired.)

Storage Temperature –55°C to +125°C

Ambient Temperature with Power Applied0°C to +70°C

Supply Voltage to Ground Potential-0.3V to +7.0V

DC Voltage Applied to Outputs in High Z State-0.3V to +7.0V

DC Input Voltage–0.3V to +7.0V Output Current into Outputs (LOW)20 mA

Operating Range

Range	Ambient Temperature	v _{cc}
Commercial	0°C to +70°C	5V ± 10%

Electrical Characteristics Over the Operating Range

					1481A	
Parameter	Description	Test Condition	Min.	Max.	Unit	
V _{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = -1.0 mA		2.4		V
V _{OL}	Output LOW Voltage	V _{CC} = Min., I _{OL} = 2.0 mA			0.4	V
V _{IH}	Input HIGH Voltage			2.2	V _{CC} + 0.3	V
V _{IL}	Input LOW Voltage			-0.3	0.8	V
I _{IX}	Input Load Current	$GND \le V_I \le V_{CC}$			+20	μA
I _{OZ}	Output Leakage Current	$GND \le V_O \le V_{CC}$, Output Disabled			+20	μA
I _{CC}	V _{CC} Operating Supply Current	$V_{CC} = Max., \overline{MS} \le V_{IL}, I_{OUT} =$	0 mA		110	mA
I _{SB1}	Automatic MS Power-Down Current	Max. V _{CC} , MS ≥ V _{IH} , Min. Duty Cycle = 100%			64	mA
I _{SB2}	Automatic MS	Max. V_{CC} , $\overline{MS} \ge V_{CC} - 0.2V$, Standard			32	mA
	Power-Down Current	$V_{IN} \ge V_{CC} - 0.2V$, or $V_{IN} \le 100$ L Version -100, -120			500	μA
			L Version –85		1600	μΑ

Capacitance^[1]

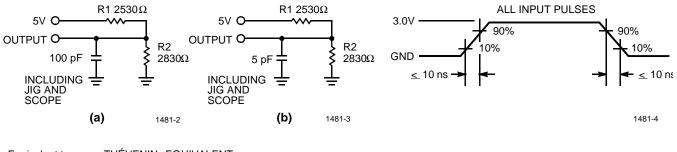
Parameter	Description	Test Conditions	CYM1481AM ax.	Unit
C _{INA}	Input Capacitance $(A_{0-16}, \overline{OE}, \overline{WE})$	$T_{A} = 25^{\circ}C, f = 1 MHz,$	125	pF
C _{INB}	Input Capacitance (A ₁₇₋₂₀ , MS)	$V_{CC} = 5.0V$	25	pF
C _{OUT}	Output Capacitance		165	pF

Note:

1. Tested on a sample basis.



AC Test Loads and Waveforms



THÉVENIN EQUIVALENT Equivalent to: 1340Ω 2.64V OUTPUT O Ô

Switching Characteristics Over the Operating Range^[2]

		1481	1481A-70		A-85	1481A-100		1481A-120		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CYCL	E									<u> </u>
t _{RC}	Read Cycle Time	70		85		100		120		ns
t _{AA}	Address to Data Valid		70		85		100		120	ns
t _{OHA}	Data Hold from Address Change	5		10		10		10		ns
t _{AMS}	MS LOW to Data Valid		70		85		100		120	ns
t _{DOE}	OE LOW to Data Valid		40		45		50		60	ns
t _{LZOE}	OE LOW to Low Z	5		5		5		5		ns
t _{HZOE}	OE HIGH to High Z ^[3]		30		30		35		45	ns
t _{LZMS}	MS LOW to Low Z ^[4]	5		10		10		10		ns
t _{HZMS}	MS HIGH to High Z ^[3, 4]		30		30		35		45	ns
WRITE CYCI	E ^[5]	•								
t _{WC}	Write Cycle Time	70		85		100		120		ns
t _{SMS}	MS LOW to Write End	65		75		90		100		ns
t _{AW}	Address Set-Up to Write End	65		75		90		100		ns
t _{HA}	Address Hold from Write End	5		7		7		7		ns
t _{SA}	Address Set-Up to Write Start	0		5		5		5		ns
t _{PWE}	WE Pulse Width	65		65		75		85		ns
t _{SD}	Data Set-Up to Write End	30		35		40		45		ns
t _{HD}	Data Hold from Write End	0		5		5		5		ns
t _{HZWE}	WE LOW to High Z ^[3]		30		30		35		40	ns
t _{LZWE}	WE HIGH to Low Z	5		5		5		5		ns

Notes:

Test conditions assume signal transition time of 10 µs or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, output loading of 1 TTL load, and 100-pF load capacitance. 2.

3.

4.

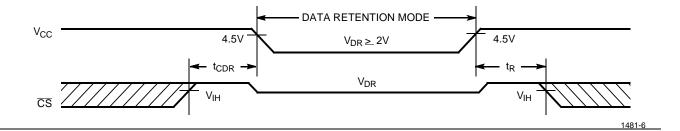
 t_{HZOE} , t_{HZMS} , and t_{HZWE} are specified with $C_L = 5 \text{ pF}$ as in part (b) of AC Test Loads and Waveforms. Transition is measured ±500 mV from steady-state voltage. At any given temperature and voltage condition, t_{HZMS} is less than t_{LZMS} for any given device. These parameters are guaranteed and not 100% tested. The internal write time of the memory is defined by the overlap of MS LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write. 5.



Data Retention Characteristics (L Version Only)

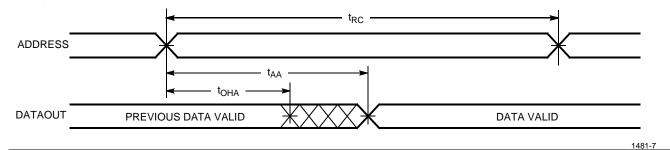
			1481A-70		1481A–85		1481A–100 148A1–120		
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Min.	Max.	Unit
V _{DR}	V _{CC} for Retention Data		2		2		2		V
I _{CCDR}	Data Retention Current	V _{DR} = 3.0V,		800		800		250	μΑ
t _{CDR} ^[6]	Chip Deselect to Data Retention Time	$\frac{V_{DR}}{MS} = 3.0V,$ $\frac{MS}{V_{CC}} = 0.2V,$ $\frac{V_{IN} \ge V_{CC}}{0.2V} \text{ or } V_{IN}$ < 0.2V	0		0		0		ns
t _R	Operation Recovery Time		5		5		5		ns

Data Retention Waveform



Switching Waveforms

Read Cycle No. 1^[7, 8]



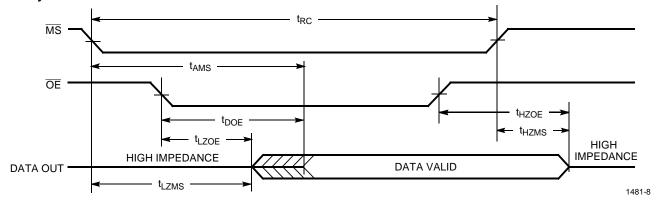
Notes:

- 6. 7.
- Guaranteed, not tested. Device is continuously selected. \overline{OE} , $\overline{MS} = V_{IL}$. Address valid prior to or coincident with \overline{MS} transition LOW. 8.

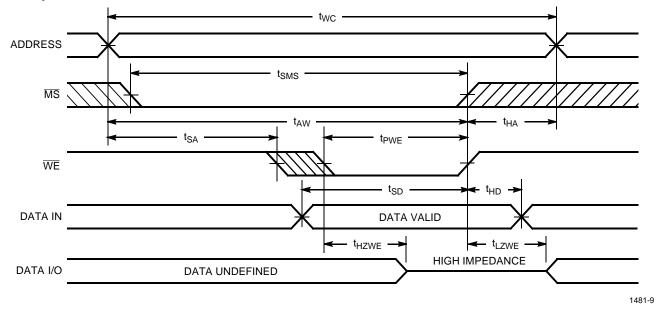


Switching Waveforms (continued)

Read Cycle No. 2^[8, 9]



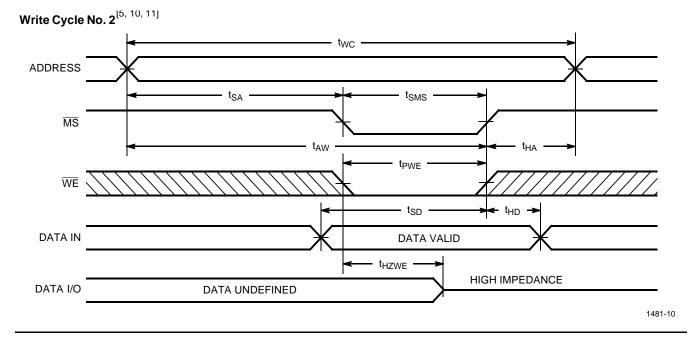




Notes: 9. WE is HIGH for read cycle. 10. Data I/O is high impedance if $\overline{OE} = V_{IH}$.



Switching Waveforms (continued)



Note: 11. If $\overline{\text{MS}}$ goes HIGH simultaneously with $\overline{\text{WE}}$ HIGH, the output remains in a high-impedance state.



Truth Table

MS	WE	OE	Input/Outputs	Mode
Н	Х	Х	High Z	Deselect/Power-Down
L	Н	L	Data Out	Read
L	L	Х	Data In	Write
L	Н	Н	High Z	Deselect

Ordering Information

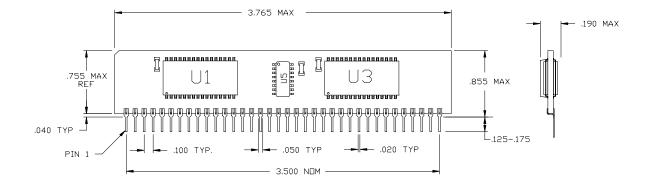
Speed (ns)	Ordering Code	Package Type	Package Type	Operating Range
70	CYM1481APS-70C	PS10	36-Pin SIP Module	Commercial
	CYM1481ALPS-70C			
85	CYM1481APS-85C	PS10	36-Pin SIP Module	Commercial
	CYM1481ALPS-85C			
100	CYM1481APS-100C	PS10	36-Pin SIP Module	Commercial
	CYM1481ALPS-100C			
120	CYM1481APS-120C	PS10	36-Pin SIP Module	Commercial
	CYM1481ALPS-120C			

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Package Diagram

36-Pin SIP Module PS10



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